

**Search Notes**

Application/Control No.

10/624,506

Examiner

Edward Wojciechowicz

Applicant(s)/Patent under  
Reexamination

BYEON ET AL.

Art Unit

2815

**SEARCHED**

Class	Subclass	Date	Examiner
757	343, 390 391, 392 396	4-27-05	ERJ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST 257/343, 390, 391, 392 Dmas; LDD	4-27-05	ERJ